IEEE Int. Workshop on Defect and Data Driven Testing (D3T-2009)
Nov. 5 – 6, Austin Convention Center, Texas

Day 1 - Thursday, Nov. 5
4:00pm - Opening Remarks: **M. Tehranipoor** (Univ. of Connecticut)

4:10pm - 5:00 pm
Thursday Keynote: Title: TBD
Magdy Abadir (Freescale)

5:10pm - 6:30pm
Session 1: Statistical Analysis and Yield
Chair – Nisar Ahmed (Texas Instruments)

30: Manufacturing Processes for End-to-End Yield Optimization (Invited Talk)
Matthias Kamm (Cisco)
30: Data in Culture of Zero Defects (Invited Talk)
LeRoy (Freescale)
20: Rapid Yield Learning through Short Loop Electrical Fault Localization
Jacob Orbon (Verigy)

Workshop Welcome Reception - 7:00pm - 9:00pm

Day 2 - Friday, Nov. 6
8:00am - 9:20 am
Tutorial: Data Collection and the New and Expanded STDF Format
Ajay Koche (Consultant)

9:30am - 10:30am
Session 2: Defect Based Testing
Chair – Kohei Miyase (KIT)

20: On-Chip Power Supply Noise Measurements
Ekarat Laohavaleeson and Chintan Patel (UMBC)
20: Verification of Convolution Relation between Sensitized Path's Gate Transients, Power Grid Impulse Responses and Power Port Transients
Reza M. Rad (UMBC), Jim Plusquellic (UNM), Chintan Patel (UMBC) and Abhishek Singh (nVidia)
20: A mechanism to address di/dt noise during delay test
Amitava Majumdar, Nehal Patel, Ramamurthy Setty, Arani Sinha (AMD)

Coffee Break- 10:30am - 10:50am

10:50am - 11:50am
Session 3: Signal Integrity and Power-Aware Test
Chair – Sankaran Menon, Intel

20: Extended Abstract: Developing a Novel Quality Metric for Path-Delay Fault Pattern Evaluation
Junxia Ma, Jeremy Lee and Mohammad Tehranipoor (UConn)

20: Optimizing the Percentage of X-Bits to Reduce Switching Activity
Isao Beppu, Kohei Miyase, Yuta Yamato, Xiaoqing Wen and Seiji Kajihara (KIT)
20: Realistic Low Cost Framework for Supply Noise Aware Delay Test Compaction
Zhongwei Jiang, Zheng Wang, Jing Wang and D. M. H. Walker (Texas A&M)

Lunch - 11:50 pm - 1:00pm

1:00pm - 2:00pm
Session 4: Industry Practices
Chair – Hank Walker (Texas A&M)

30: Statistical Outlier Method Applications
Amit Nahar, Kenneth Butler, John Carulli and Charles Weinberger (Texas Instruments)
30: Title
Anne Gattiker (IBM)

Short Break- 2:00 pm - 2:20pm

2:20pm - 4:00 pm **- Panel Discussion**
Test and Diagnosis for Parametric Failures

Organizers:
Mohammad Tehranipoor (UConn)
Al Crouch (Asset-Intertech)

Panelists:
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